

DTM4926 www.din-tek.jp

Dual N-Channel 30-V (D-S) MOSFET

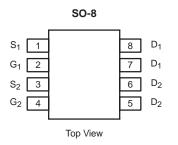
PRODUCT SUMMARY						
V <sub>DS</sub> (V)	R <sub>DS(on)</sub> (Ω)	I <sub>D</sub> (A)	Q <sub>g</sub> (Typ.)			
30	0.008 at $V_{GS}$ = 10 V	8	15 nC			
	0.011 at V <sub>GS</sub> = 4.5 V	6.8	15110			

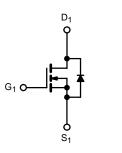
#### **FEATURES**

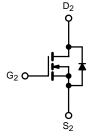
- DT-Trench Power MOSFET
- 100 % UIS Tested
- 100 % R<sub>g</sub> Tested Compliant to RoHS Directive 2002/95/EC •

#### **APPLICATIONS**

- Set Top Box
- Low Current DC/DC







N-Channel MOSFET

N-Channel MOSFET

ABSOLUTE MAXIMUM RATIN	<b>IGS</b> T <sub>A</sub> = 25 °C,	unless othe	erwise noted	
Parameter	Symbol	Limit	Unit	
Drain-Source Voltage		V <sub>DS</sub>	30	V
Gate-Source Voltage		V <sub>GS</sub>	± 20	v
	T <sub>C</sub> = 25 °C	I <sub>D</sub>	8 <sup>a</sup>	
Continuous Drain Current (T <sub>.1</sub> = 150 °C)	T <sub>C</sub> = 70 °C		6.2	
	T <sub>A</sub> = 25 °C		7.2 <sup>b, c</sup>	
	T <sub>A</sub> = 70 °C		6.2 <sup>b, c</sup>	Α
Pulsed Drain Current		I <sub>DM</sub>	40	
Continuous Source-Drain Diode Current	T <sub>C</sub> = 25 °C	la.	2.25	
	$T_A = 25 \text{ °C}$		1.48 <sup>b, c</sup>	
Single Pulse Avalanche Current L = 0.1 mH		I <sub>AS</sub>	5	
Single Pulse Avalanche Energy	L = 0.1 mm	E <sub>AS</sub>	1.25	mJ
	T <sub>C</sub> = 25 °C		2.7	
Maximum Power Dissipation	T <sub>C</sub> = 70 °C	P <sub>D</sub>	1.77	w
	T <sub>A</sub> = 25 °C		1.78 <sup>b, c</sup>	vv
	T <sub>A</sub> = 70 °C	1	1.14 <sup>b, c</sup>	
Operating Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>stg</sub>	- 55 to 150	°C

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient <sup>a, c, d</sup>	t ≤ 10 s	R <sub>thJA</sub>	58	70	°C/W	
Maximum Junction-to-Foot (Drain)	Steady State	R <sub>thJF</sub>	38	45	0/11	

Notes:

a. Package limited,  $T_C = 25 \ ^{\circ}C$ .

b. Surface Mounted on 1" x 1" FR4 board.

c. t = 10 s.

d. Maximum under Steady State conditions is 110 °C/W.

COMPLIANT

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Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static	1 - 1		1	1		
Drain-Source Breakdown Voltage	V <sub>DS</sub>	V <sub>GS</sub> = 0 V, I <sub>D</sub> = 250 μA	30			V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	1 050 14		32		mV/°C
V <sub>GS(th)</sub> Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I <sub>D</sub> = 250 μA		- 5.0		
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}$ , $I_D = 250 \ \mu A$	1.0		3.0	V
Gate-Source Leakage	I <sub>GSS</sub>	$V_{DS} = 0 V, V_{GS} = \pm 20 V$			± 100	nA
Zero Gate Voltage Drain Current		$V_{DS} = 30 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$			1	
	DSS	$V_{DS} = 30$ V, $V_{GS} = 0$ V, $T_{J} = 55$ °C			10	μA
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	40			А
		V <sub>GS</sub> = 10 V, I <sub>D</sub> = 5 A		0.008	0.009	Ω
Drain-Source On-State Resistance <sup>a</sup>	R <sub>DS(on)</sub>	V <sub>GS</sub> = 4.5 V, I <sub>D</sub> = 4 A		0.011	0.013	
Forward Transconductance <sup>a</sup>	9 <sub>fs</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 5 A		16		S
Dynamic <sup>b</sup>	I I					
Input Capacitance	C <sub>iss</sub>			586		pF
Output Capacitance	C <sub>oss</sub>	$V_{DS}$ = 15 V, $V_{GS}$ = 0 V, f = 1 MHz		117		
Reverse Transfer Capacitance	C <sub>rss</sub>			55		
Tatal Oata Ohanna	0	$V_{DS} = 15 \text{ V}, V_{GS} = 10 \text{ V}, I_{D} = 5 \text{ A}$		15		nC
Total Gate Charge	Qg			3.7	5.6	
Gate-Source Charge	Q <sub>gs</sub>	$V_{DS}$ = 15 V, $V_{GS}$ = 4.5 V, $I_{D}$ = 5 A		1.4		
Gate-Drain Charge	Q <sub>gd</sub>			1.05		
Gate Resistance	Rg	f = 1 MHz	0.8	4.3	8.6	Ω
Turn-On Delay Time	t <sub>d(on)</sub>			12	24	ns
Rise Time	t <sub>r</sub>	$V_{DD}$ = 15 V, $R_L$ = 3 $\Omega$		55	100	
Turn-Off Delay Time	t <sub>d(off)</sub>	$\text{I}_{\text{D}}\cong \text{5}$ A, $\text{V}_{\text{GEN}}$ = 4.5 V, $\text{R}_{\text{g}}$ = 1 $\Omega$		11	22	
Fall Time	t <sub>f</sub>			8	16	
Turn-On Delay Time	t <sub>d(on)</sub>			4	8	
Rise Time	t <sub>r</sub>	$V_{DD}$ = 15 V, R <sub>L</sub> = 3 $\Omega$		9	18	
Turn-Off Delay Time	t <sub>d(off)</sub>	$\text{I}_\text{D} \cong \text{5}$ A, $\text{V}_\text{GEN}$ = 10 V, $\text{R}_\text{g}$ = 1 $\Omega$		10	20	
Fall Time	t <sub>f</sub>			6	12	
Drain-Source Body Diode Characteristi	cs					
Continuous Source-Drain Diode Current	۱ <sub>S</sub>	T <sub>C</sub> = 25 °C			6.25	^
Pulse Diode Forward Current	I <sub>SM</sub>				24	A
Body Diode Voltage	V <sub>SD</sub>	$I_{S} = 2 \text{ A}, V_{GS} = 0 \text{ V}$		0.8	1.2	V
Body Diode Reverse Recovery Time	t <sub>rr</sub>			11	20	ns
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>	I <sub>F</sub> = 5 A, dl/dt = 100 A/μs, T <sub>J</sub> = 25 °C		4	8	nC
Reverse Recovery Fall Time	ta	$r_F = 3 \text{ A}, \text{ u/ul} = 100 \text{ A/}\mu\text{s}, 1 \text{ J} = 23 \text{ C}$		7	1	ns
Reverse Recovery Rise Time	t <sub>b</sub>	1		4		

Notes:

a. Pulse test; pulse width  $\leq$  300 µs, duty cycle  $\leq$  2 %

b. Guaranteed by design, not subject to production testing.

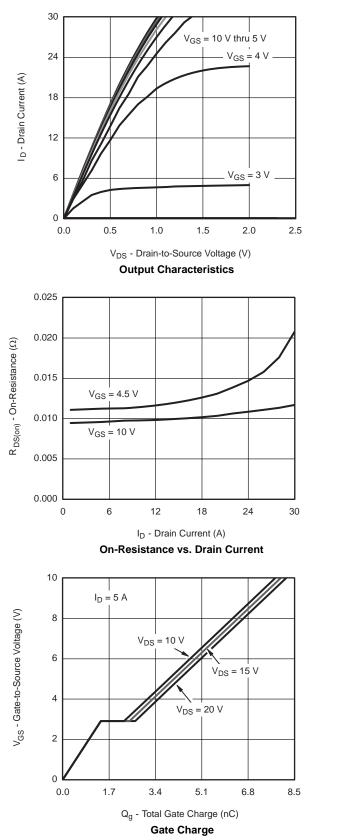
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

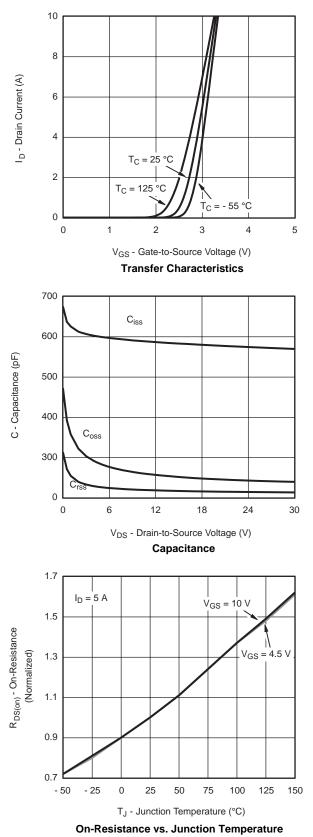
**Din-Tek** SEMICONDUCTOR

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- 0.7

- 1.0

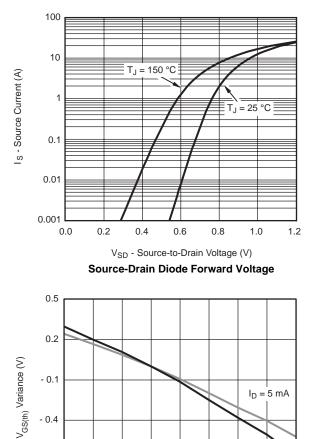
- 50

- 25

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#### TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



25

50

T<sub>J</sub> - Temperature (°C)

**Threshold Voltage** 

0

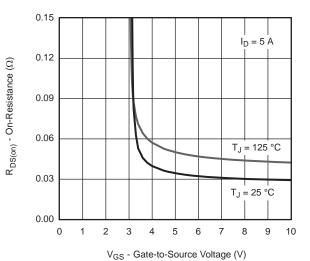
 $I_D = 250 \ \mu A$ 

100

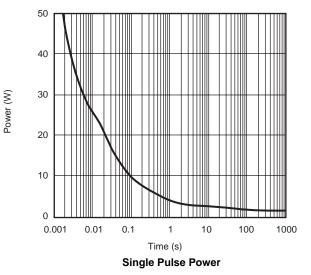
125

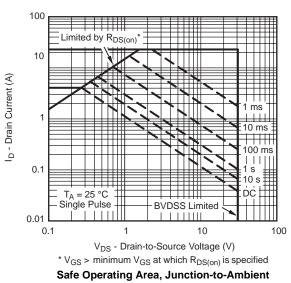
150

75



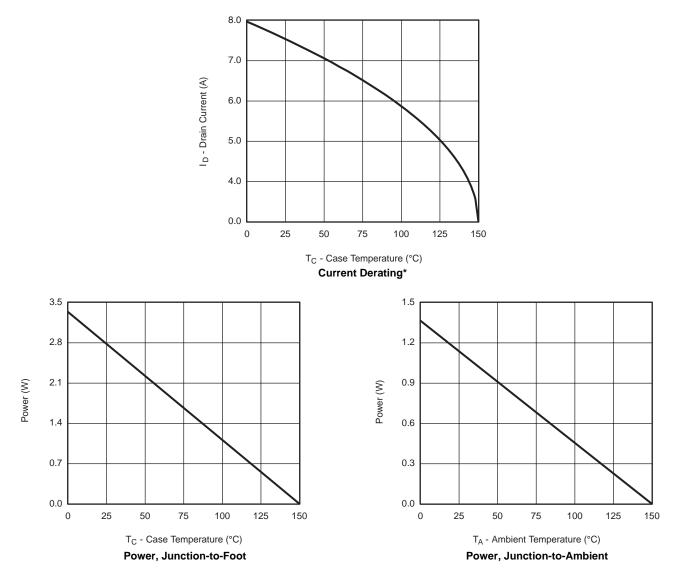
On-Resistance vs. Gate-to-Source Voltage







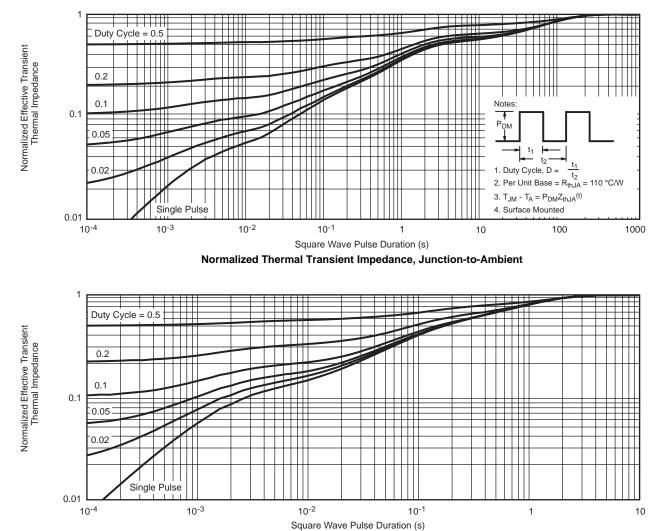
#### TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



\* The power dissipation  $P_D$  is based on  $T_{J(max)} = 150$  °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

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#### TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



Normalized Thermal Transient Impedance, Junction-to-Foot



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